

Description

The vs65N03-T2 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

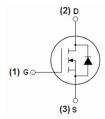
- V_{DS} =30V,I_D =65A
 - $R_{DS(ON)}$ <7.0m Ω @ V_{GS} =10V

 $R_{DS(ON)} < 9.5 \text{m}\Omega$ @ $V_{GS} = 5V$

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VS65N03-T2	VS65N03-T2	TO-252-2L	-	-	-

Absolute Maximum Ratings (T_c=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage	V _{GS}	±20	V	
Drain Current-Continuous	I _D	65	Α	
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	46	Α	
Pulsed Drain Current	I _{DM}	200	Α	
Maximum Power Dissipation	P _D	65	W	
Derating factor		0.43	W/°C	
Single pulse avalanche energy (Note 5)	E _{AS}	150	mJ	
Operating Junction and Storage Temperature Range	T_J, T_STG	-55 To 175	$^{\circ}$	

Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	R _{eJC}	2.3	°C/W	



Electrical Characteristics (TC=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	30	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)				,		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250μA	1	1.5	2.5	V
Drain-Source On-State Resistance	В	V _{GS} =10V, I _D =20A	-	5.7	7.0	
	R _{DS(ON)}	V _{GS} =4.5V, I _D =20A	-	7.7	9.5	mΩ
Forward Transconductance	g FS	V _{DS} =5V,I _D =20A	20	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}	151/11/ 01/	-	1400	-	PF
Output Capacitance	Coss	V_{DS} =15V, V_{GS} =0V, F=1.0MHz	-	205	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVIHZ	-	177	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =5V,I _D =20A	-	9	-	nS
Turn-on Rise Time	t _r		-	8	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10V, R_{GEN} =6 Ω	-	28	-	nS
Turn-Off Fall Time	t _f		-	5	-	nS
Total Gate Charge	Qg	\/ -45\/ L -20A	-	32.3	-	nC
Gate-Source Charge	Q _{gs}	$V_{DS}=15V,I_{D}=20A,$ $V_{GS}=10V$	-	4.9	-	nC
Gate-Drain Charge	Q_{gd}	V _{GS} -10V	-	6.9	-	nC
Drain-Source Diode Characteristics	•	•		,		
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =20A	-	0.85	1.2	V
Diode Forward Current (Note 2)	Is		-	-	65	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, I _F = 20A	-	-	27	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	-	20	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

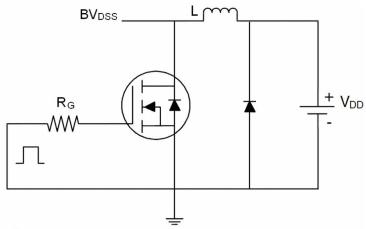
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300 μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition: Tj=25 $^{\circ}\text{C}$,VDD=15V,VG=10V,L=0.5mH,Rg=25 Ω

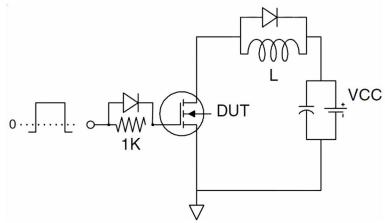


Test Circuit

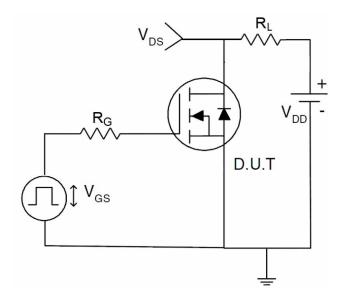
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit



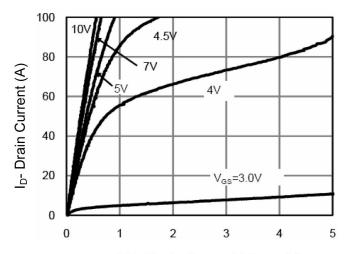
3) Switch Time Test Circuit





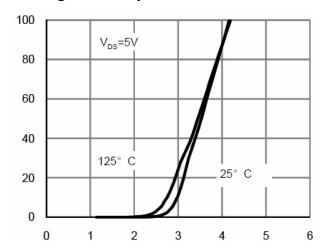
Ip- Drain Current (A)

Typical Electrical and Thermal Characteristics (Curves)



Vds Drain-Source Voltage (V)





Vgs Gate-Source Voltage (V)
Figure 2 Transfer Characteristics

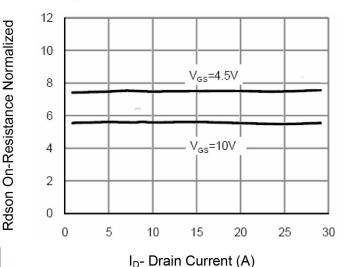


Figure 3 Rdson- Drain Current

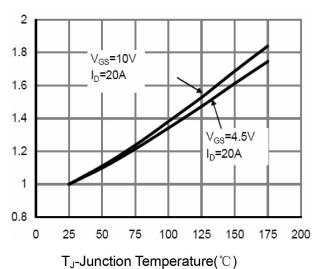
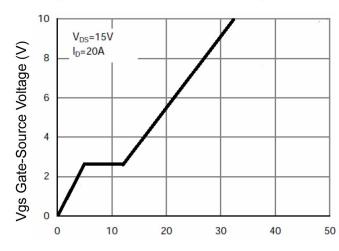
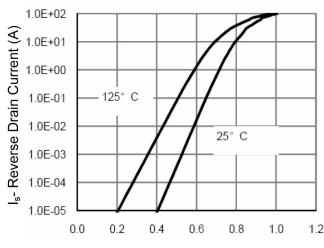


Figure 4 Rdson-JunctionTemperature



Qg Gate Charge (nC)
Figure 5 Gate Charge



Vsd Source-Drain Voltage (V)

Figure 6 Source- Drain Diode Forward



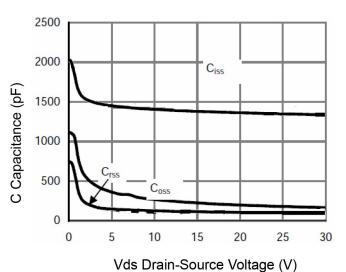
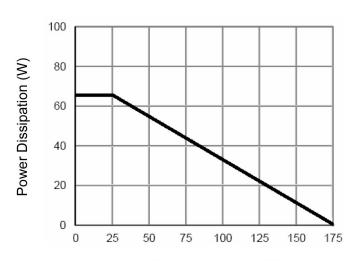


Figure 7 Capacitance vs Vds



 T_J -Junction Temperature($^{\circ}$ C) Figure 9 Power De-rating

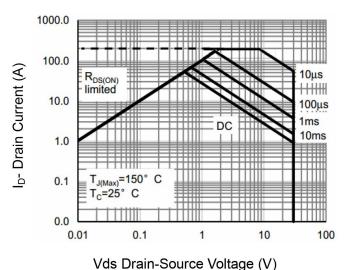


Figure 8 Safe Operation Area

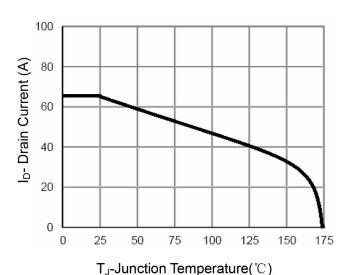


Figure 10 ID Current- Junction Temperature

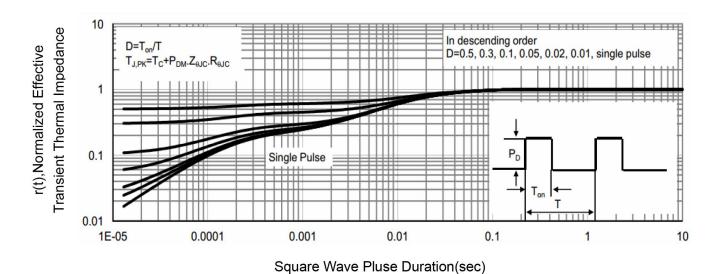


Figure 11 Normalized Maximum Transient Thermal Impedance

Vseei Semiconductor Co., Ltd